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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	9216
Total RAM Bits	55296
Number of I/O	194
Number of Gates	400000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/agl400v2-fg484i

Table 2-3 • Flash Programming Limits – Retention, Storage, and Operating Temperature¹

Product Grade	Programming Cycles	Program Retention (biased/unbiased)	Maximum Storage Temperature T _{STG} (°C) ²	Maximum Operating Junction Temperature T _J (°C) ²
Commercial	500	20 years	110	100
Industrial	500	20 years	110	100

Notes:

1. This is a stress rating only; functional operation at any condition other than those indicated is not implied.
2. These limits apply for program/data retention only. Refer to Table 2-1 on page 2-1 and Table 2-2 on page 2-2 for device operating conditions and absolute limits.

Table 2-4 • Overshoot and Undershoot Limits¹

VCCI	Average VCCI–GND Overshoot or Undershoot Duration as a Percentage of Clock Cycle ²	Maximum Overshoot/Undershoot ²
2.7 V or less	10%	1.4 V
	5%	1.49 V
3 V	10%	1.1 V
	5%	1.19 V
3.3 V	10%	0.79 V
	5%	0.88 V
3.6 V	10%	0.45 V
	5%	0.54 V

Notes:

1. Based on reliability requirements at junction temperature at 85°C.
2. The duration is allowed at one out of six clock cycles. If the overshoot/undershoot occurs at one out of two cycles, the maximum overshoot/undershoot has to be reduced by 0.15 V.
3. This table does not provide PCI overshoot/undershoot limits.

I/O Power-Up and Supply Voltage Thresholds for Power-On Reset (Commercial and Industrial)

Sophisticated power-up management circuitry is designed into every IGLOO device. These circuits ensure easy transition from the powered-off state to the powered-up state of the device. The many different supplies can power up in any sequence with minimized current spikes or surges. In addition, the I/O will be in a known state through the power-up sequence. The basic principle is shown in Figure 2-1 on page 2-4 and Figure 2-2 on page 2-5.

There are five regions to consider during power-up.

IGLOO I/Os are activated only if ALL of the following three conditions are met:

1. VCC and VCCI are above the minimum specified trip points (Figure 2-1 on page 2-4 and Figure 2-2 on page 2-5).
2. VCCI > VCC – 0.75 V (typical)
3. Chip is in the operating mode.

VCCI Trip Point:

Ramping up (V5 devices): 0.6 V < trip_point_up < 1.2 V

Ramping down (V5 Devices): 0.5 V < trip_point_down < 1.1 V

Ramping up (V2 devices): 0.75 V < trip_point_up < 1.05 V

Ramping down (V2 devices): 0.65 V < trip_point_down < 0.95 V

VCC Trip Point:

Ramping up (V5 devices): 0.6 V < trip_point_up < 1.1 V

Ramping down (V5 devices): 0.5 V < trip_point_down < 1.0 V

Table 2-17 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings¹
Applicable to Standard Plus I/O Banks

	C _{LOAD} (pF)	VCCI (V)	Static Power PDC7 (mW) ²	Dynamic Power PAC10 (μW/MHz) ³
Single-Ended				
3.3 V LVTTTL / 3.3 V LVCMOS	5	3.3	–	122.16
3.3 V LVCMOS Wide Range ⁴	5	3.3	–	122.16
2.5 V LVCMOS	5	2.5	–	68.37
1.8 V LVCMOS	5	1.8	–	34.53
1.5 V LVCMOS (JESD8-11)	5	1.5	–	23.66
1.2 V LVCMOS ⁵	5	1.2	–	14.90
1.2 V LVCMOS Wide Range ⁵	5	1.2	–	14.90
3.3 V PCI	10	3.3	–	181.06
3.3 V PCI-X	10	3.3	–	181.06

Notes:

1. Dynamic power consumption is given for standard load and software default drive strength and output slew.
2. P_{DC7} is the static power (where applicable) measured on VCCI.
3. P_{AC10} is the total dynamic power measured on VCCI.
4. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.
5. Applicable for IGLOO V2 devices only.

Table 2-18 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings¹
Applicable to Standard I/O Banks

	C _{LOAD} (pF)	VCCI (V)	Static Power PDC7 (mW) ²	Dynamic Power PAC10 (μW/MHz) ³
Single-Ended				
3.3 V LVTTTL / 3.3 V LVCMOS	5	3.3	–	104.38
3.3 V LVCMOS Wide Range ⁴	5	3.3	–	104.38
2.5 V LVCMOS	5	2.5	–	59.86
1.8 V LVCMOS	5	1.8	–	31.26
1.5 V LVCMOS (JESD8-11)	5	1.5	–	21.96
1.2 V LVCMOS ⁵	5	1.2	–	13.49
1.2 V LVCMOS Wide Range ⁵	5	1.2	–	13.49

Notes:

1. Dynamic power consumption is given for standard load and software default drive strength and output slew.
2. PDC7 is the static power (where applicable) measured on VCCI.
3. PAC10 is the total dynamic power measured on VCCI.
4. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.
5. Applicable for IGLOO V2 devices only.

**Table 2-28 • Summary of Maximum and Minimum DC Input Levels
Applicable to Commercial and Industrial Conditions**

DC I/O Standards	Commercial ¹		Industrial ²	
	IIL ⁴	IIH ⁵	IIL ⁴	IIH ⁵
	μA	μA	μA	μA
3.3 V LVTTTL / 3.3 V LVCMOS	10	10	15	15
3.3 V LVCMOS Wide Range	10	10	15	15
2.5 V LVCMOS	10	10	15	15
1.8 V LVCMOS	10	10	15	15
1.5 V LVCMOS	10	10	15	15
1.2 V LVCMOS ³	10	10	15	15
1.2 V LVCMOS Wide Range ³	10	10	15	15
3.3 V PCI	10	10	15	15
3.3 V PCI-X	10	10	15	15

Notes:

1. Commercial range ($0^{\circ}\text{C} < T_A < 70^{\circ}\text{C}$)
2. Industrial range ($-40^{\circ}\text{C} < T_A < 85^{\circ}\text{C}$)
3. Applicable to V2 Devices operating at $V_{CCI} \geq V_{CC}$.
4. IIL is the input leakage current per I/O pin over recommended operation conditions where $-0.3\text{ V} < V_{IN} < V_{IL}$.
5. IIH is the input leakage current per I/O pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges

3.3 V LVC MOS Wide Range

Table 2-63 • Minimum and Maximum DC Input and Output Levels for LVC MOS 3.3 V Wide Range
Applicable to Advanced I/O Banks

3.3 V LVC MOS Wide Range		VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL ²	IIH ³
Drive Strength	Equivalent Software Default Drive Strength Option ¹	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	μA	μA	Max. mA ⁴	Max. mA ⁴	μA^5	μA^5
100 μA	2 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	25	27	10	10
100 μA	4 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	25	27	10	10
100 μA	6 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	51	54	10	10
100 μA	8 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	51	54	10	10
100 μA	12 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	103	109	10	10
100 μA	16 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	132	127	10	10
100 μA	24 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	268	181	10	10

Notes:

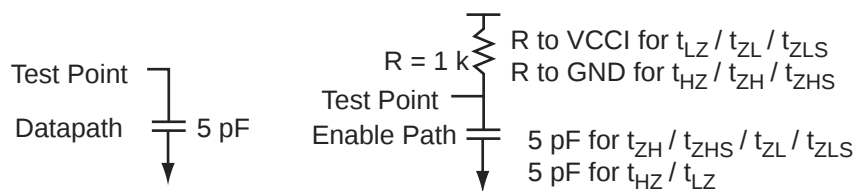
1. The minimum drive strength for any LVC MOS 3.3 V software configuration when run in wide range is $\pm 100 \mu\text{A}$. Drive strengths displayed in software are supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
2. IIL is the input leakage current per I/O pin over recommended operation conditions where $-0.3 \text{ V} < V_{\text{IN}} < V_{\text{IL}}$.
3. IIH is the input leakage current per I/O pin over recommended operating conditions $V_{\text{IH}} < V_{\text{IN}} < V_{\text{CCI}}$. Input current is larger when operating outside recommended ranges
4. Currents are measured at 100°C junction temperature and maximum voltage.
5. Currents are measured at 85°C junction temperature.
6. Software default selection highlighted in gray.

Table 2-81 • Minimum and Maximum DC Input and Output Levels
Applicable to Standard I/O Banks

2.5 V LVCMOS	VIL		VIH		VOL	VOH	IOL	IOH	IOSH	IOSL	IIL ¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μA ⁴
2 mA	−0.3	0.7	1.7	3.6	0.7	1.7	2	2	16	18	10	10
4 mA	−0.3	0.7	1.7	3.6	0.7	1.7	4	4	16	18	10	10
6 mA	−0.3	0.7	1.7	3.6	0.7	1.7	6	6	32	37	10	10
8 mA	−0.3	0.7	1.7	3.6	0.7	1.7	8	8	32	37	10	10

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where $-0.3\text{ V} < V_{IN} < V_{IL}$.
2. IIH is the input leakage current per I/O pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges
3. Currents are measured at 100°C junction temperature and maximum voltage.
4. Currents are measured at 85°C junction temperature.
5. Software default selection highlighted in gray.

**Figure 2-8 • AC Loading****Table 2-82 • AC Waveforms, Measuring Points, and Capacitive Loads**

Input Low (V)	Input High (V)	Measuring Point* (V)	C _{LOAD} (pF)
0	2.5	1.2	5

Note: *Measuring point = Vtrip. See Table 2-29 on page 2-28 for a complete table of trip points.

Timing Characteristics

Applies to 1.5 V DC Core Voltage

Table 2-83 • 2.5 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.97	4.96	0.18	1.08	0.66	5.06	4.59	2.26	2.00	8.66	8.19	ns
4 mA	Std.	0.97	4.96	0.18	1.08	0.66	5.06	4.59	2.26	2.00	8.66	8.19	ns
6 mA	Std.	0.97	4.15	0.18	1.08	0.66	4.24	3.94	2.54	2.51	7.83	7.53	ns
8 mA	Std.	0.97	4.15	0.18	1.08	0.66	4.24	3.94	2.54	2.51	7.83	7.53	ns
12 mA	Std.	0.97	3.57	0.18	1.08	0.66	3.65	3.47	2.73	2.84	7.24	7.06	ns
16 mA	Std.	0.97	3.39	0.18	1.08	0.66	3.46	3.36	2.78	2.92	7.06	6.95	ns
24 mA	Std.	0.97	3.38	0.18	1.08	0.66	3.38	3.38	2.83	3.25	6.98	6.98	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-84 • 2.5 V LVCMOS High Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.97	2.77	0.18	1.08	0.66	2.83	2.60	2.26	2.08	6.42	6.19	ns
4 mA	Std.	0.97	2.77	0.18	1.08	0.66	2.83	2.60	2.26	2.08	6.42	6.19	ns
6 mA	Std.	0.97	2.34	0.18	1.08	0.66	2.39	2.08	2.54	2.60	5.99	5.68	ns
8 mA	Std.	0.97	2.34	0.18	1.08	0.66	2.39	2.08	2.54	2.60	5.99	5.68	ns
12 mA	Std.	0.97	2.09	0.18	1.08	0.66	2.14	1.83	2.73	2.93	5.73	5.43	ns
16 mA	Std.	0.97	2.05	0.18	1.08	0.66	2.09	1.78	2.78	3.02	5.69	5.38	ns
24 mA	Std.	0.97	2.06	0.18	1.08	0.66	2.10	1.72	2.83	3.35	5.70	5.32	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-85 • 2.5 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V

Applicable to Standard Plus Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.97	4.42	0.18	1.08	0.66	4.51	4.10	1.96	1.85	8.10	7.69	ns
4 mA	Std.	0.97	4.42	0.18	1.08	0.66	4.51	4.10	1.96	1.85	8.10	7.69	ns
6 mA	Std.	0.97	3.62	0.18	1.08	0.66	3.70	3.52	2.21	2.32	7.29	7.11	ns
8 mA	Std.	0.97	3.62	0.18	1.08	0.66	3.70	3.52	2.21	2.32	7.29	7.11	ns
12 mA	Std.	0.97	3.09	0.18	1.08	0.66	3.15	3.09	2.39	2.61	6.74	6.68	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-104 • 1.8 V LVC MOS High Slew – Applies to 1.5 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 1.7 V****Applicable to Standard Banks**

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	Std.	2.62	0.18	0.98	0.66	2.67	2.59	1.67	1.29	2.62	ns
4 mA	Std.	2.18	0.18	0.98	0.66	2.22	1.93	1.97	2.06	2.18	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

1.2 V DC Core Voltage**Table 2-105 • 1.8 V LVC MOS Low Slew – Applies to 1.2 V DC Core Voltage****Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.7 V****Applicable to Advanced I/O Banks**

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	6.97	0.26	1.11	1.10	7.08	6.48	2.87	2.29	12.87	12.27	ns
4 mA	Std.	1.55	5.91	0.26	1.11	1.10	6.01	5.57	3.21	3.14	11.79	11.36	ns
6 mA	Std.	1.55	5.16	0.26	1.11	1.10	5.24	4.95	3.45	3.55	11.03	10.74	ns
8 mA	Std.	1.55	4.90	0.26	1.11	1.10	4.98	4.81	3.50	3.66	10.77	10.60	ns
12 mA	Std.	1.55	4.83	0.26	1.11	1.10	4.90	4.83	3.58	4.08	10.68	10.61	ns
16 mA	Std.	1.55	4.83	0.26	1.11	1.10	4.90	4.83	3.58	4.08	10.68	10.61	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-106 • 1.8 V LVC MOS High Slew – Applies to 1.2 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.7 V****Applicable to Advanced I/O Banks**

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	3.73	0.26	1.11	1.10	3.71	3.73	2.86	2.34	9.49	9.51	ns
4 mA	Std.	1.55	3.12	0.26	1.11	1.10	3.16	2.97	3.21	3.22	8.95	8.75	ns
6 mA	Std.	1.55	2.79	0.26	1.11	1.10	2.83	2.59	3.45	3.65	8.62	8.38	ns
8 mA	Std.	1.55	2.73	0.26	1.11	1.10	2.77	2.52	3.50	3.75	8.56	8.30	ns
12 mA	Std.	1.55	2.72	0.26	1.11	1.10	2.76	2.43	3.58	4.19	8.55	8.22	ns
16 mA	Std.	1.55	2.72	0.26	1.11	1.10	2.76	2.43	3.58	4.19	8.55	8.22	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-123 • 1.5 V LVC MOS Low Slew – Applies to 1.2 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V****Applicable to Standard Plus Banks**

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	6.43	0.26	1.27	1.10	6.54	5.95	2.82	2.83	12.32	11.74	ns
4 mA	Std.	1.55	5.59	0.26	1.27	1.10	5.68	5.27	3.07	3.27	11.47	11.05	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-124 • 1.5 V LVC MOS High Slew – Applies to 1.2 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V****Applicable to Standard Plus Banks**

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	1.55	3.02	0.26	1.27	1.10	3.07	2.81	2.82	2.92	8.85	8.59	ns
4 mA	Std.	1.55	2.68	0.26	1.27	1.10	2.72	2.39	3.07	3.37	8.50	8.18	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-125 • 1.5 V LVC MOS Low Slew – Applies to 1.2 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V****Applicable to Standard Banks**

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	Std.	1.55	6.35	0.26	1.22	1.10	6.46	5.93	2.40	2.46	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-126 • 1.5 V LVC MOS High Slew – Applies to 1.2 V DC Core Voltage**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V****Applicable to Standard Banks**

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	Std.	1.55	2.92	0.26	1.22	1.10	2.96	2.60	2.40	2.56	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

B-LVDS/M-LVDS

Bus LVDS (B-LVDS) and Multipoint LVDS (M-LVDS) specifications extend the existing LVDS standard to high-performance multipoint bus applications. Multidrop and multipoint bus configurations may contain any combination of drivers, receivers, and transceivers. Microsemi LVDS drivers provide the higher drive current required by B-LVDS and M-LVDS to accommodate the loading. The drivers require series terminations for better signal quality and to control voltage swing. Termination is also required at both ends of the bus since the driver can be located anywhere on the bus. These configurations can be implemented using the TRIBUF_LVDS and BIBUF_LVDS macros along with appropriate terminations. Multipoint designs using Microsemi LVDS macros can achieve up to 200 MHz with a maximum of 20 loads. A sample application is given in Figure 2-14. The input and output buffer delays are available in the LVDS section in Table 2-149 on page 2-81 and Table 2-150 on page 2-81.

Example: For a bus consisting of 20 equidistant loads, the following terminations provide the required differential voltage, in worst-case Industrial operating conditions, at the farthest receiver: $R_S = 60\ \Omega$ and $R_T = 70\ \Omega$, given $Z_0 = 50\ \Omega$ (2") and $Z_{stub} = 50\ \Omega$ (~1.5").

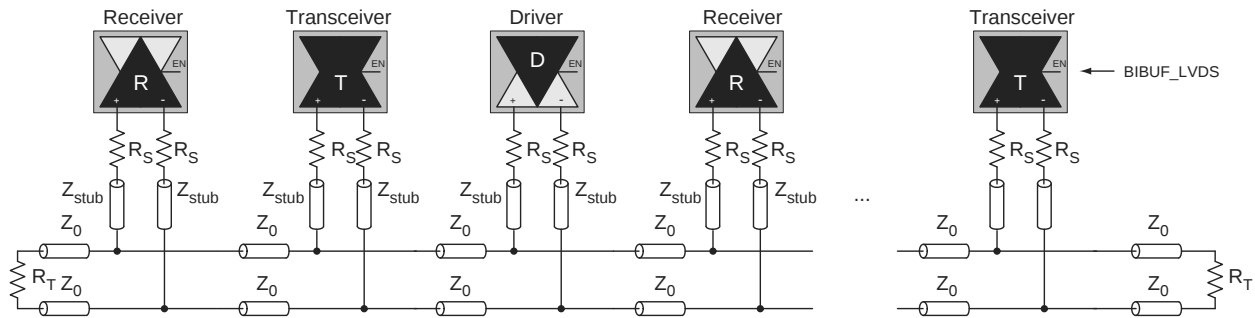


Figure 2-14 • B-LVDS/M-LVDS Multipoint Application Using LVDS I/O Buffers

LVPECL

Low-Voltage Positive Emitter-Coupled Logic (LVPECL) is another differential I/O standard. It requires that one data bit be carried through two signal lines. Like LVDS, two pins are needed. It also requires external resistor termination.

The full implementation of the LVDS transmitter and receiver is shown in an example in Figure 2-15. The building blocks of the LVPECL transmitter-receiver are one transmitter macro, one receiver macro, three board resistors at the transmitter end, and one resistor at the receiver end. The values for the three driver resistors are different from those used in the LVDS implementation because the output standard specifications are different.

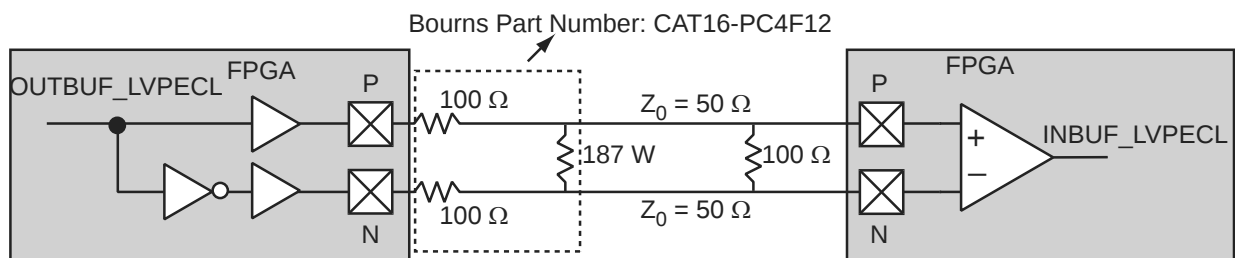


Figure 2-15 • LVPECL Circuit Diagram and Board-Level Implementation

Table 2-155 • Parameter Definition and Measuring Nodes

Parameter Name	Parameter Definition	Measuring Nodes (from, to)*
t_{OCLKQ}	Clock-to-Q of the Output Data Register	H, DOUT
t_{OSUD}	Data Setup Time for the Output Data Register	F, H
t_{OHD}	Data Hold Time for the Output Data Register	F, H
t_{OSUE}	Enable Setup Time for the Output Data Register	G, H
t_{OHE}	Enable Hold Time for the Output Data Register	G, H
t_{OPRE2Q}	Asynchronous Preset-to-Q of the Output Data Register	L, DOUT
$t_{OREMPRE}$	Asynchronous Preset Removal Time for the Output Data Register	L, H
$t_{ORECPRE}$	Asynchronous Preset Recovery Time for the Output Data Register	L, H
t_{OECLKQ}	Clock-to-Q of the Output Enable Register	H, EOUT
t_{OESUD}	Data Setup Time for the Output Enable Register	J, H
t_{OEHD}	Data Hold Time for the Output Enable Register	J, H
t_{OESUE}	Enable Setup Time for the Output Enable Register	K, H
t_{OEHE}	Enable Hold Time for the Output Enable Register	K, H
$t_{OEPRE2Q}$	Asynchronous Preset-to-Q of the Output Enable Register	I, EOUT
$t_{OEREMPRE}$	Asynchronous Preset Removal Time for the Output Enable Register	I, H
$t_{OERECPRE}$	Asynchronous Preset Recovery Time for the Output Enable Register	I, H
t_{ICLKQ}	Clock-to-Q of the Input Data Register	A, E
t_{ISUD}	Data Setup Time for the Input Data Register	C, A
t_{IHD}	Data Hold Time for the Input Data Register	C, A
t_{ISUE}	Enable Setup Time for the Input Data Register	B, A
t_{IHE}	Enable Hold Time for the Input Data Register	B, A
t_{IPRE2Q}	Asynchronous Preset-to-Q of the Input Data Register	D, E
$t_{IREMPRE}$	Asynchronous Preset Removal Time for the Input Data Register	D, A
$t_{IRECPRE}$	Asynchronous Preset Recovery Time for the Input Data Register	D, A

Note: *See Figure 2-16 on page 2-84 for more information.

Table 2-183 • AGL060 Global Resource**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$**

Parameter	Description	Std.		Units
		Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	2.04	2.33	ns
t_{RCKH}	Input High Delay for Global Clock	2.10	2.51	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	1.40		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	1.65		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.40	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-184 • AGL125 Global Resource**Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$**

Parameter	Description	Std.		Units
		Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	2.08	2.54	ns
t_{RCKH}	Input High Delay for Global Clock	2.15	2.77	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	1.40		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	1.65		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.62	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

3 – Pin Descriptions

Supply Pins

GND**Ground**

Ground supply voltage to the core, I/O outputs, and I/O logic.

GNDQ**Ground (quiet)**

Quiet ground supply voltage to input buffers of I/O banks. Within the package, the GNDQ plane is decoupled from the simultaneous switching noise originated from the output buffer ground domain. This minimizes the noise transfer within the package and improves input signal integrity. GNDQ must always be connected to GND on the board.

VCC**Core Supply Voltage**

Supply voltage to the FPGA core, nominally 1.5 V for IGLOO V5 devices, and 1.2 V or 1.5 V for IGLOO V2 devices. VCC is required for powering the JTAG state machine in addition to VJTAG. Even when a device is in bypass mode in a JTAG chain of interconnected devices, both VCC and VJTAG must remain powered to allow JTAG signals to pass through the device.

For IGLOO V2 devices, VCC can be switched dynamically from 1.2 V to 1.5 V or vice versa. This allows in-system programming (ISP) when VCC is at 1.5 V and the benefit of low power operation when VCC is at 1.2 V.

VCCIBx**I/O Supply Voltage**

Supply voltage to the bank's I/O output buffers and I/O logic. Bx is the I/O bank number. There are up to eight I/O banks on IGLOO devices plus a dedicated VJTAG bank. Each bank can have a separate VCCI connection. All I/Os in a bank will run off the same VCCIBx supply. VCCI can be 1.2 V, 1.5 V, 1.8 V, 2.5 V, or 3.3 V, nominal voltage. Unused I/O banks should have their corresponding VCCI pins tied to GND.

VMVx**I/O Supply Voltage (quiet)**

Quiet supply voltage to the input buffers of each I/O bank. x is the bank number. Within the package, the VMV plane biases the input stage of the I/Os in the I/O banks. This minimizes the noise transfer within the package and improves input signal integrity. Each bank must have at least one VMV connection, and no VMV should be left unconnected. All I/Os in a bank run off the same VMVx supply. VMV is used to provide a quiet supply voltage to the input buffers of each I/O bank. VMVx can be 1.2 V, 1.5 V, 1.8 V, 2.5 V, or 3.3 V, nominal voltage. Unused I/O banks should have their corresponding VMV pins tied to GND. VMV and VCCI should be at the same voltage within a given I/O bank. Used VMV pins must be connected to the corresponding VCCI pins of the same bank (i.e., VMV0 to VCCIB0, VMV1 to VCCIB1, etc.).

VCCPLA/B/C/D/E/F**PLL Supply Voltage**

Supply voltage to analog PLL, nominally 1.5 V or 1.2 V.

- 1.5 V for IGLOO V5 devices
- 1.2 V or 1.5 V for IGLOO V2 devices

When the PLLs are not used, the Microsemi Designer place-and-route tool automatically disables the unused PLLs to lower power consumption. The user should tie unused VCCPLx and VCOMPLx pins to ground. Microsemi recommends tying VCCPLx to VCC and using proper filtering circuits to decouple VCC noise from the PLLs. Refer to the PLL Power Supply Decoupling section of the "Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs" chapter of the *IGLOO FPGA Fabric User Guide* for a complete board solution for the PLL analog power supply and ground.

- There is one VCCPLF pin on IGLOO devices.

VCOMPLA/B/C/D/E/F**PLL Ground**

Ground to analog PLL power supplies. When the PLLs are not used, the Microsemi Designer place-and-route tool automatically disables the unused PLLs to lower power consumption. The user should tie unused VCCPLx and VCOMPLx pins to ground.

There is one VCOMPLF pin on IGLOO devices.

CS196	
Pin Number	AGL125 Function
A1	GND
A2	GAA0/IO00RSB0
A3	GAC0/IO04RSB0
A4	GAC1/IO05RSB0
A5	IO09RSB0
A6	IO15RSB0
A7	IO18RSB0
A8	IO22RSB0
A9	IO27RSB0
A10	GBC0/IO35RSB0
A11	GBB0/IO37RSB0
A12	GBB1/IO38RSB0
A13	GBA1/IO40RSB0
A14	GND
B1	VCCIB1
B2	VMV0
B3	GAA1/IO01RSB0
B4	GAB1/IO03RSB0
B5	GND
B6	IO16RSB0
B7	IO20RSB0
B8	IO24RSB0
B9	IO28RSB0
B10	GND
B11	GBC1/IO36RSB0
B12	GBA0/IO39RSB0
B13	GBA2/IO41RSB0
B14	GBB2/IO43RSB0
C1	GAC2/IO128RSB1
C2	GAB2/IO130RSB1
C3	GNDQ
C4	VCCIB0
C5	GAB0/IO02RSB0
C6	IO14RSB0
C7	VCCIB0
C8	NC

CS196	
Pin Number	AGL125 Function
C9	IO23RSB0
C10	IO29RSB0
C11	VCCIB0
C12	IO42RSB0
C13	GNDQ
C14	IO44RSB0
D1	IO127RSB1
D2	IO129RSB1
D3	GAA2/IO132RSB1
D4	IO126RSB1
D5	IO06RSB0
D6	IO13RSB0
D7	IO19RSB0
D8	IO21RSB0
D9	IO26RSB0
D10	IO31RSB0
D11	IO30RSB0
D12	VMV0
D13	IO46RSB0
D14	GBC2/IO45RSB0
E1	IO125RSB1
E2	GND
E3	IO131RSB1
E4	VCCIB1
E5	NC
E6	IO08RSB0
E7	IO17RSB0
E8	IO12RSB0
E9	IO11RSB0
E10	NC
E11	VCCIB0
E12	IO32RSB0
E13	GND
E14	IO34RSB0
F1	IO124RSB1
F2	IO114RSB1

CS196	
Pin Number	AGL125 Function
F3	IO113RSB1
F4	IO112RSB1
F5	IO111RSB1
F6	NC
F7	VCC
F8	VCC
F9	NC
F10	IO07RSB0
F11	IO25RSB0
F12	IO10RSB0
F13	IO33RSB0
F14	IO47RSB0
G1	GFB1/IO121RSB1
G2	GFA0/IO119RSB1
G3	GFA2/IO117RSB1
G4	VCOMPLF
G5	GFC0/IO122RSB1
G6	VCC
G7	GND
G8	GND
G9	VCC
G10	GCC0/IO52RSB0
G11	GCB1/IO53RSB0
G12	GCA0/IO56RSB0
G13	IO48RSB0
G14	GCC2/IO59RSB0
H1	GFB0/IO120RSB1
H2	GFA1/IO118RSB1
H3	VCCPLF
H4	GFB2/IO116RSB1
H5	GFC1/IO123RSB1
H6	VCC
H7	GND
H8	GND
H9	VCC
H10	GCC1/IO51RSB0

CS281	
Pin Number	AGL1000 Function
H8	VCC
H9	VCCIB0
H10	VCC
H11	VCCIB0
H12	VCC
H13	VCCIB1
H15	IO90NPB1
H16	GCB0/IO92NPB1
H18	GCA1/IO93PPB1
H19	GCA2/IO94PPB1
J1	VCOMPLF
J2	GFA0/IO207NDB3
J4	VCCPLF
J5	GFC0/IO209NPB3
J7	GFA2/IO206PDB3
J8	VCCIB3
J9	GND
J10	GND
J11	GND
J12	VCCIB1
J13	GCC1/IO91PPB1
J15	GCA0/IO93NPB1
J16	GCB2/IO95PPB1
J18	IO94NPB1
J19	IO102PSB1
K1	VCCIB3
K2	GFA1/IO207PDB3
K4	GND
K5	IO204NPB3
K7	IO206NDB3
K8	VCC
K9	GND
K10	GND
K11	GND
K12	VCC
K13	GCC2/IO96PPB1

CS281	
Pin Number	AGL1000 Function
K15	IO95NPB1
K16	GND
K18	IO96NPB1
K19	VCCIB1
L1	GFB2/IO205PDB3
L2	IO205NDB3
L4	GFC2/IO204PPB3
L5	IO203PPB3
L7	IO203NPB3
L8	VCCIB3
L9	GND
L10	GND
L11	GND
L12	VCCIB1
L13	IO103PPB1
L15	IO103NPB1
L16	IO97PPB1
L18	IO98NPB1
L19	IO97NPB1
M1	IO202PDB3
M2	IO202NDB3
M4	IO201NPB3
M5	IO198PPB3
M7	VCCIB3
M8	VCC
M9	VCCIB2
M10	VCC
M11	VCCIB2
M12	VCC
M13	VCCIB1
M15	IO104NPB1
M16	IO100NPB1
M18	IO104PPB1
M19	IO98PPB1
N1	IO201PPB3
N2	IO198NPB3

CS281	
Pin Number	AGL1000 Function
N4	IO196PPB3
N5	IO197NPB3
N7	GEA2/IO187RSB2
N8	VCCIB2
N9	IO155RSB2
N10	IO154RSB2
N11	IO150RSB2
N12	VCCIB2
N13	VPUMP
N15	IO107PPB1
N16	IO105PPB1
N18	IO107NPB1
N19	IO100PPB1
P1	IO195PDB3
P2	GND
P3	IO195NDB3
P4	IO194PPB3
P5	GEA0/IO188NPB3
P15	IO108NDB1
P16	IO108PDB1
P17	GDC1/IO111PPB1
P18	GND
P19	IO105NPB1
R1	IO196NPB3
R2	IO194NPB3
R4	GEC1/IO190PPB3
R5	GEB1/IO189PPB3
R6	IO184RSB2
R7	IO173RSB2
R8	IO168RSB2
R9	IO160RSB2
R10	IO151RSB2
R11	IO141RSB2
R12	IO136RSB2
R13	IO127RSB2
R14	IO124RSB2

QN132	
Pin Number	AGL125 Function
C17	IO83RSB1
C18	VCCIB1
C19	TCK
C20	VMV1
C21	VPUMP
C22	VJTAG
C23	VCCIB0
C24	NC
C25	NC
C26	GCA1/IO55RSB0
C27	GCC0/IO52RSB0
C28	VCCIB0
C29	IO42RSB0
C30	GNDQ
C31	GBA1/IO40RSB0
C32	GBB0/IO37RSB0
C33	VCC
C34	IO24RSB0
C35	IO19RSB0
C36	IO16RSB0
C37	IO10RSB0
C38	VCCIB0
C39	GAB1/IO03RSB0
C40	VMV0
D1	GND
D2	GND
D3	GND
D4	GND

VQ100	
Pin Number	AGL060 Function
1	GND
2	GAA2/IO51RSB1
3	IO52RSB1
4	GAB2/IO53RSB1
5	IO95RSB1
6	GAC2/IO94RSB1
7	IO93RSB1
8	IO92RSB1
9	GND
10	GFB1/IO87RSB1
11	GFB0/IO86RSB1
12	VCOMPLF
13	GFA0/IO85RSB1
14	VCCPLF
15	GFA1/IO84RSB1
16	GFA2/IO83RSB1
17	VCC
18	VCCIB1
19	GEC1/IO77RSB1
20	GEB1/IO75RSB1
21	GEB0/IO74RSB1
22	GEA1/IO73RSB1
23	GEA0/IO72RSB1
24	VMV1
25	GNDQ
26	GEA2/IO71RSB1
27	FF/GEB2/IO70RSB1
28	GEC2/IO69RSB1
29	IO68RSB1
30	IO67RSB1
31	IO66RSB1
32	IO65RSB1
33	IO64RSB1
34	IO63RSB1
35	IO62RSB1
36	IO61RSB1

VQ100	
Pin Number	AGL060 Function
37	VCC
38	GND
39	VCCIB1
40	IO60RSB1
41	IO59RSB1
42	IO58RSB1
43	IO57RSB1
44	GDC2/IO56RSB1
45	GDB2/IO55RSB1
46	GDA2/IO54RSB1
47	TCK
48	TDI
49	TMS
50	VMV1
51	GND
52	VPUMP
53	NC
54	TDO
55	TRST
56	VJTAG
57	GDA1/IO49RSB0
58	GDC0/IO46RSB0
59	GDC1/IO45RSB0
60	GCC2/IO43RSB0
61	GCB2/IO42RSB0
62	GCA0/IO40RSB0
63	GCA1/IO39RSB0
64	GCC0/IO36RSB0
65	GCC1/IO35RSB0
66	VCCIB0
67	GND
68	VCC
69	IO31RSB0
70	GBC2/IO29RSB0
71	GBB2/IO27RSB0
72	IO26RSB0

VQ100	
Pin Number	AGL060 Function
73	GBA2/IO25RSB0
74	VMV0
75	GNDQ
76	GBA1/IO24RSB0
77	GBA0/IO23RSB0
78	GBB1/IO22RSB0
79	GBB0/IO21RSB0
80	GBC1/IO20RSB0
81	GBC0/IO19RSB0
82	IO18RSB0
83	IO17RSB0
84	IO15RSB0
85	IO13RSB0
86	IO11RSB0
87	VCCIB0
88	GND
89	VCC
90	IO10RSB0
91	IO09RSB0
92	IO08RSB0
93	GAC1/IO07RSB0
94	GAC0/IO06RSB0
95	GAB1/IO05RSB0
96	GAB0/IO04RSB0
97	GAA1/IO03RSB0
98	GAA0/IO02RSB0
99	IO01RSB0
100	IO00RSB0

FG256	
Pin Number	AGL400 Function
R5	IO123RSB2
R6	IO118RSB2
R7	IO112RSB2
R8	IO106RSB2
R9	IO100RSB2
R10	IO96RSB2
R11	IO89RSB2
R12	IO85RSB2
R13	GDB2/IO81RSB2
R14	TDI
R15	NC
R16	TDO
T1	GND
T2	IO126RSB2
T3	FF/GEB2/IO133RSB2
T4	IO124RSB2
T5	IO116RSB2
T6	IO113RSB2
T7	IO107RSB2
T8	IO105RSB2
T9	IO102RSB2
T10	IO97RSB2
T11	IO92RSB2
T12	GDC2/IO82RSB2
T13	IO86RSB2
T14	GDA2/IO80RSB2
T15	TMS
T16	GND

FG484	
Pin Number	AGL400 Function
M3	NC
M4	GFA2/IO144PPB3
M5	GFA1/IO145PDB3
M6	VCCPLF
M7	IO143NDB3
M8	GFB2/IO143PDB3
M9	VCC
M10	GND
M11	GND
M12	GND
M13	GND
M14	VCC
M15	GCB2/IO71PPB1
M16	GCA1/IO69PPB1
M17	GCC2/IO72PPB1
M18	NC
M19	GCA2/IO70PDB1
M20	NC
M21	NC
M22	NC
N1	NC
N2	NC
N3	NC
N4	GFC2/IO142PDB3
N5	IO144NPB3
N6	IO141PPB3
N7	IO120RSB2
N8	VCCIB3
N9	VCC
N10	GND
N11	GND
N12	GND
N13	GND
N14	VCC
N15	VCCIB1
N16	IO71NPB1

FG484	
Pin Number	AGL1000 Function
E13	IO51RSB0
E14	IO57RSB0
E15	GBC1/IO73RSB0
E16	GBB0/IO74RSB0
E17	IO71RSB0
E18	GBA2/IO78PDB1
E19	IO81PDB1
E20	GND
E21	NC
E22	IO84PDB1
F1	NC
F2	IO215PDB3
F3	IO215NDB3
F4	IO224NDB3
F5	IO225NDB3
F6	VMV3
F7	IO11RSB0
F8	GAC0/IO04RSB0
F9	GAC1/IO05RSB0
F10	IO25RSB0
F11	IO36RSB0
F12	IO42RSB0
F13	IO49RSB0
F14	IO56RSB0
F15	GBC0/IO72RSB0
F16	IO62RSB0
F17	VMV0
F18	IO78NDB1
F19	IO81NDB1
F20	IO82PPB1
F21	NC
F22	IO84NDB1
G1	IO214NDB3
G2	IO214PDB3
G3	NC
G4	IO222NDB3

Revision	Changes	Page
Revision 23 (December 2012)	The "IGLOO Ordering Information" section has been updated to mention "Y" as "Blank" mentioning "Device Does Not Include License to Implement IP Based on the Cryptography Research, Inc. (CRI) Patent Portfolio" (SAR 43173).	III
	The note in Table 2-189 · IGLOO CCC/PLL Specification and Table 2-190 · IGLOO CCC/PLL Specification referring the reader to SmartGen was revised to refer instead to the online help associated with the core (SAR 42564). Additionally, note regarding SSOs was added.	2-115, 2-116
	Live at Power-Up (LAPU) has been replaced with 'Instant On'.	NA
Revision 22 (September 2012)	The "Security" section was modified to clarify that Microsemi does not support read-back of programmed data.	1-2
	Libero Integrated Design Environment (IDE) was changed to Libero System-on-Chip (SoC) throughout the document (SAR 40271).	N/A
Revision 21 (May 2012)	Under AGL125, in the Package Pin list, CS121 was incorrectly added to the datasheet in revision 19 and has been removed (SAR 38217).	I to IV
	Corrected the inadvertent error for Max Values for LVPECL VIH and revised the same to '3.6' in Table 2-151 · Minimum and Maximum DC Input and Output Levels (SAR 37685).	2-82
	Figure 2-38 · FIFO Read and Figure 2-39 · FIFO Write have been added (SAR 34841).	2-127
	The following sentence was removed from the VMVx description in the "Pin Descriptions" section: "Within the package, the VMV plane is decoupled from the simultaneous switching noise originating from the output buffer VCCI domain" and replaced with "Within the package, the VMV plane biases the input stage of the I/Os in the I/O banks" (SAR 38317). The datasheet mentions that "VMV pins must be connected to the corresponding VCCI pins" for an ESD enhancement.	3-1